

Search Notes

Application/Control No.

10/802,529

Examiner

Jinhee J. Lee

Applicant(s)/Patent under
Reexamination

BACHINSKI ET AL.

Art Unit

2831

SEARCHED

Class	Subclass	Date	Examiner
174	121A	5/31/2005	LEE
↓	135	↓	↓
↓	48	↓	↓
439	622	↓	↓

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
174	as above	5/31/2005	LEE
439	as above	5/31/2005	LEE

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR